



ALPHA & OMEGA
SEMICONDUCTOR

AOC3878

12V Common-Drain Dual N-Channel MOSFET

General Description

- Trench Power MOSFET technology
- Low $R_{SS(ON)}$
- With ESD protection to improve battery performance and safety
- Common drain configuration for design simplicity
- RoHS and Halogen-Free Compliant

Applications

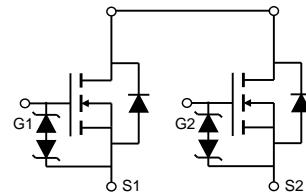
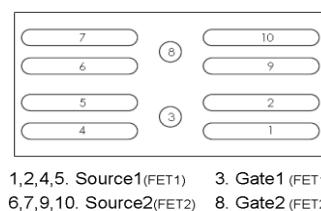
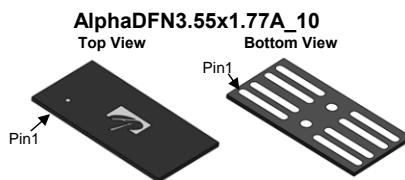
- Battery protection switch
- Mobile device battery charging and discharging

Product Summary

V_{SS}	12V
$R_{SS(ON)}$ (at $V_{GS}=4.5V$)	< 2mΩ
$R_{SS(ON)}$ (at $V_{GS}=4.0V$)	< 2.1mΩ
$R_{SS(ON)}$ (at $V_{GS}=3.8V$)	< 2.2mΩ
$R_{SS(ON)}$ (at $V_{GS}=3.1V$)	< 2.7mΩ
$R_{SS(ON)}$ (at $V_{GS}=2.5V$)	< 3.3mΩ

Typical ESD protection

HBM Class 2



Orderable Part Number	Package Type	Form	Minimum Order Quantity
AOC3878	AlphaDFN3.55x1.77A_10	Tape & Reel	5000

Absolute Maximum Ratings $T_A=25^\circ C$ unless otherwise noted

Parameter	Symbol	Rating	Units
Source-Source Voltage	V_{SS}	12	V
Gate-Source Voltage	V_{GS}	± 8	V
Source Current(DC) ^{Note1}	I_S $T_A=25^\circ C$	35	A
Source Current(Pulse) ^{Note2}	I_{SM}	130	
Power Dissipation ^{Note1}	P_D $T_A=25^\circ C$	3.1	W
Junction and Storage Temperature Range	T_J, T_{STG}	-55 to 150	°C

Thermal Characteristics

Parameter	Symbol	Typical	Units
Maximum Junction-to-Ambient	$t \leq 10s$	$R_{\theta JA}$	$^{\circ}C/W$
Maximum Junction-to-Ambient	Steady-State	40	$^{\circ}C/W$

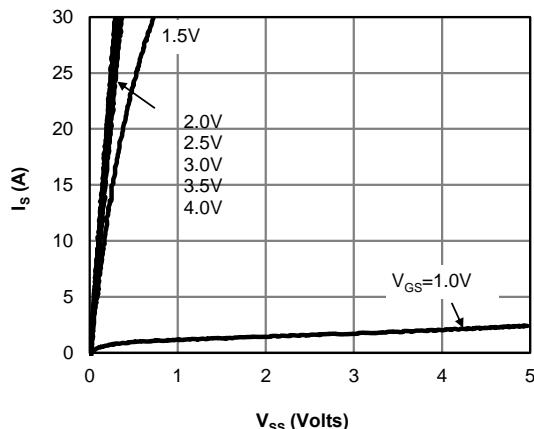
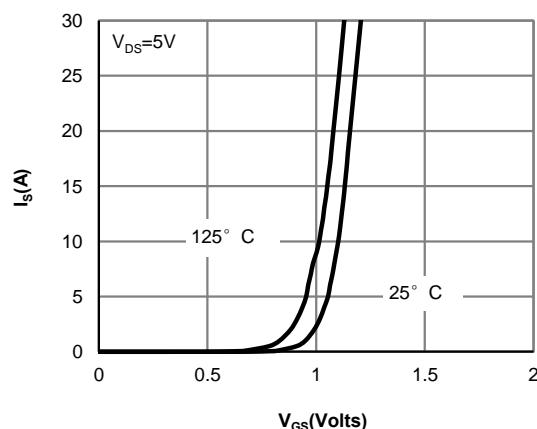
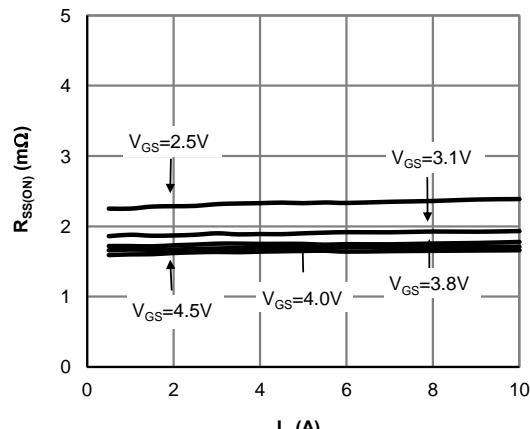
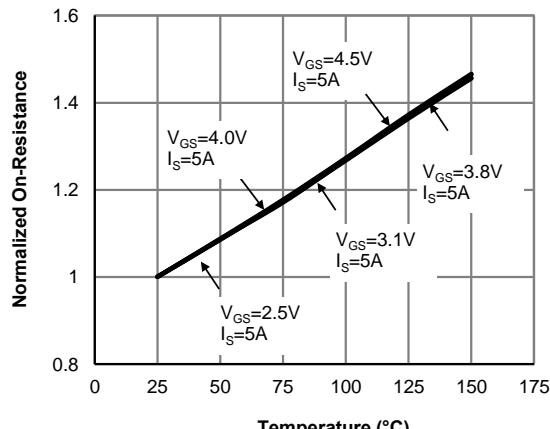
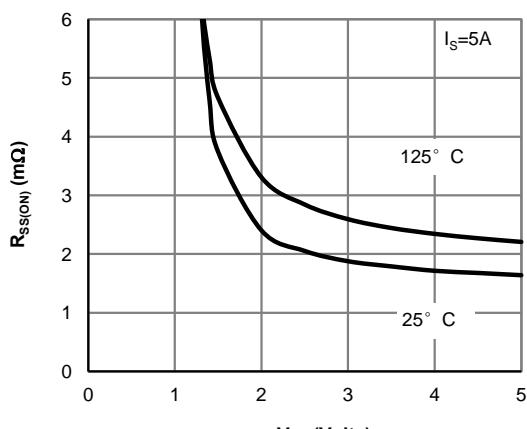
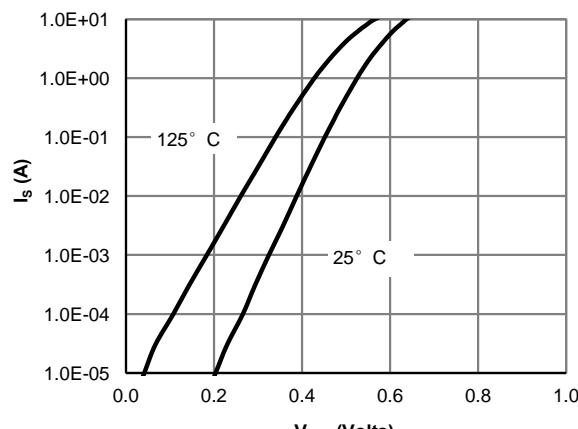
Note 1. I_S rated value is based on bare silicon. Mounted on 70mmx70mm FR-4 board.

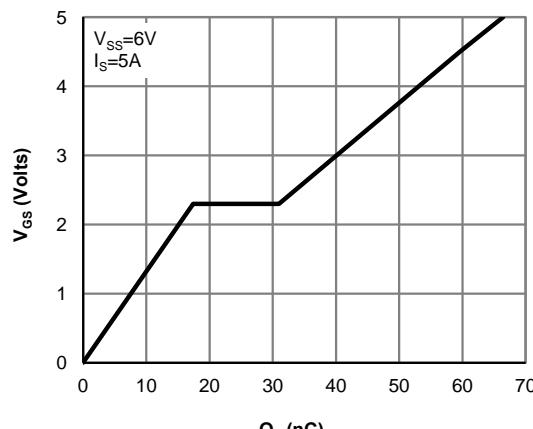
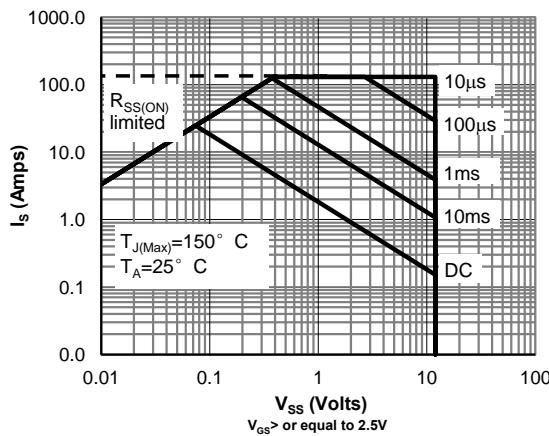
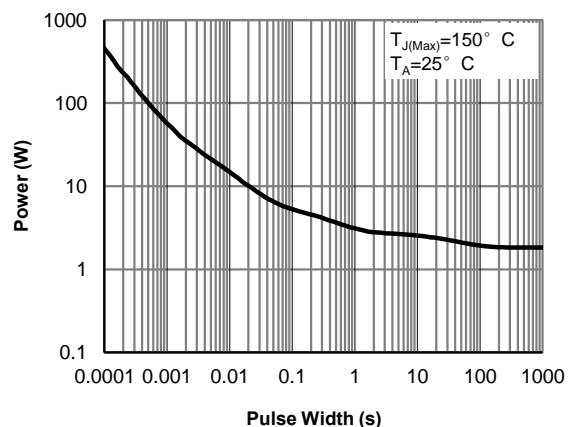
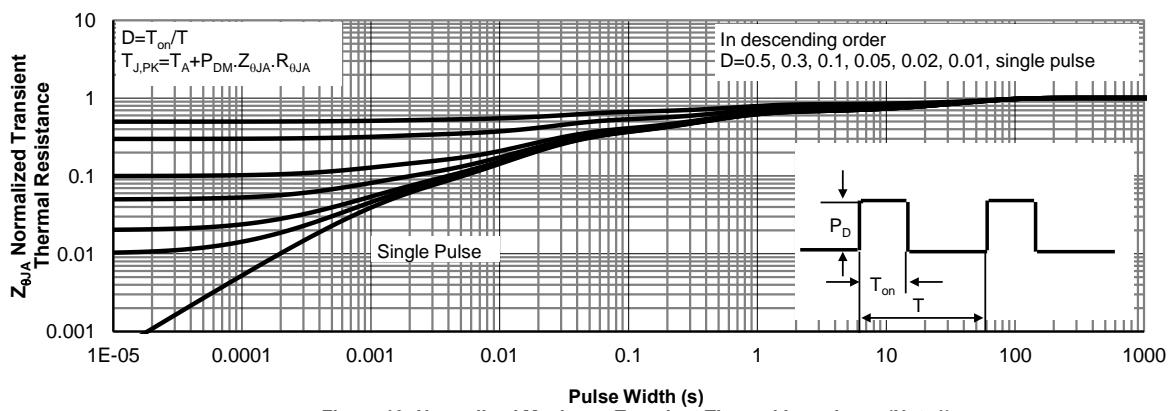
Note 2. PW <10 μs pulses, duty cycle 1% max.

Electrical Characteristics ($T_J=25^\circ\text{C}$ unless otherwise noted)

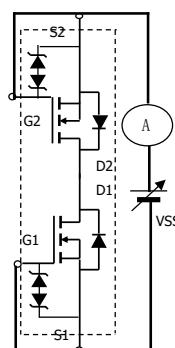
Symbol	Parameter	Conditions	Min	Typ	Max	Units	
STATIC PARAMETERS							
BV_{SSS}	Source-Source Breakdown Voltage	$I_S=250\mu\text{A}, V_{GS}=0\text{V}$	Test Circuit 6	12		V	
I_{SSS}	Zero Gate Voltage Source Current	$V_{SS}=12\text{V}, V_{GS}=0\text{V}$	Test Circuit 1 $T_J=55^\circ\text{C}$		1 5	μA	
I_{GSS}	Gate leakage current	$V_{SS}=0\text{V}, V_{GS}=\pm 8\text{V}$	Test Circuit 2		± 10	μA	
$V_{GS(\text{th})}$	Gate Threshold Voltage	$V_{SS}=V_{GS}, I_S=250\mu\text{A}$	Test Circuit 3	0.4	0.7	1.1	V
$R_{SS(\text{ON})}$	Static Source to Source On-Resistance	$V_{GS}=4.5\text{V}, I_S=5\text{A}$	Test Circuit 4	1.1	1.65	2.0	$\text{m}\Omega$
		$T_J=125^\circ\text{C}$		1.5	2.25	2.7	
		$V_{GS}=4.0\text{V}, I_S=5\text{A}$	Test Circuit 4	1.2	1.7	2.1	$\text{m}\Omega$
		$V_{GS}=3.8\text{V}, I_S=5\text{A}$	Test Circuit 4	1.25	1.75	2.2	$\text{m}\Omega$
		$V_{GS}=3.1\text{V}, I_S=5\text{A}$	Test Circuit 4	1.35	1.95	2.7	$\text{m}\Omega$
g_{FS}	Forward Transconductance	$V_{SS}=5\text{V}, I_S=5\text{A}$	Test Circuit 4	1.6	2.3	3.3	$\text{m}\Omega$
		$I_S=1\text{A}, V_{GS}=0\text{V}$	Test Circuit 5		0.52	1	V
DYNAMIC PARAMETERS							
R_g	Gate resistance	$f=1\text{MHz}$		1.0		$\text{k}\Omega$	
SWITCHING PARAMETERS							
Q_g	Total Gate Charge	$V_{G1S1}=4.5\text{V}, V_{SS}=6\text{V}, I_S=5\text{A}$		60		nC	
$t_{D(\text{on})}$	Turn-On DelayTime			2.1		μs	
t_r	Turn-On Rise Time	$V_{G1S1}=4.5\text{V}, V_{SS}=6\text{V}, R_L=1.2\Omega,$ $R_{\text{GEN}}=3\Omega$	Test	4.3		μs	
$t_{D(\text{off})}$	Turn-Off DelayTime	C_{Circuit8}		3.1		μs	
t_f	Turn-Off Fall Time			14		μs	

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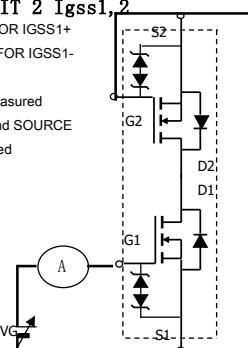
TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

Figure 1: On-Region Characteristics

Figure 2: Transfer Characteristics

Figure 3: On-Resistance vs. Source Current and Gate Voltage

Figure 4: On-Resistance vs. Junction Temperature

Figure 5: On-Resistance vs. Gate-Source Voltage

Figure 6: Forward Source to Source Characteristics

TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

Figure 7: Gate-Charge Characteristics

Figure 8: Maximum Forward Biased Safe Operating Area (Note1)

Figure 9: Single Pulse Power Rating Junction-to-Ambient (Note1)

Figure 10: Normalized Maximum Transient Thermal Impedance (Note1)

TEST CIRCUIT 1 Isss
POSITIVE VSS FOR ISSS+
NEGATIVE VSS FOR ISSS-

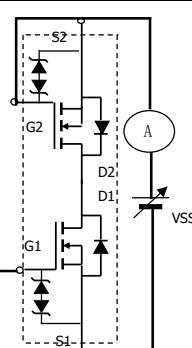


TEST CIRCUIT 2 Igss1,2
POSITIVE VGS FOR IGSS1+
NEGATIVE VGS FOR IGSS1-



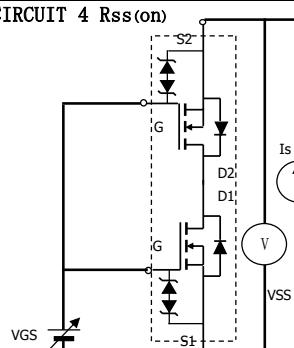
TEST CIRCUIT 3 Vgs(off)

When FET1 is measured
between GATE and SOURCE
of FET2 are shorted



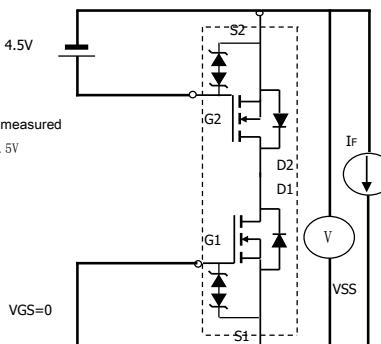
TEST CIRCUIT 4 Rss(on)

Vss/Is



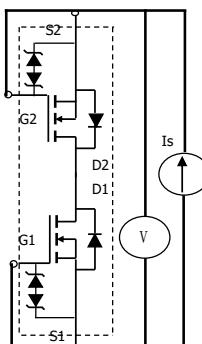
TEST CIRCUIT 5 VF(ss)1,2

When FET1 measured
FET2 VGS=4.5V



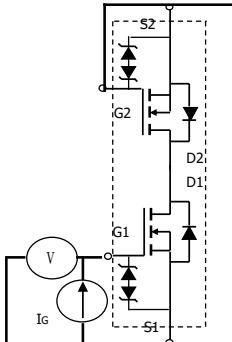
TEST CIRCUIT 6 BVdss

POSITIVE VSS FOR ISSS+
NEGATIVE VSS FOR ISSS-



TEST CIRCUIT 7 BVgs01,2
POSITIVE VSS FOR ISSS+
NEGATIVE VSS FOR ISSS-

When FET1 is measured
between GATE and SOURCE
of FET2 are shorted



TEST CIRCUIT 8
Switching time

